

-100V P-Channel Enhancement Mode MOSFET

Description

The AP5P10SI uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

General Features

$V_{DS} = -100V$ $I_D = -5.8A$

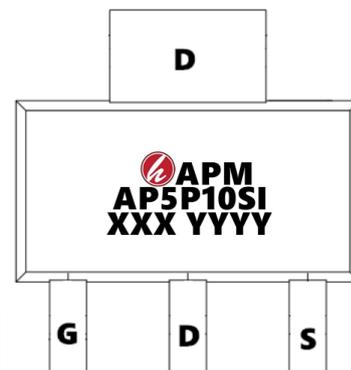
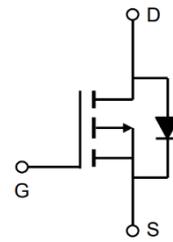
$R_{DS(ON)} < 290m\Omega$ @ $V_{GS} = -10V$ (Type: **235mΩ**)

Application

Brushless motor

Load switch

Uninterruptible power supply



Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
AP5P10SI	SOT89-3L	AP5P10SI XXX YYYY	3000

Absolute Maximum Ratings ($T_C = 25^\circ C$ unless otherwise noted)

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	-100	V
V_{GS}	Gate-Source Voltage	± 20	V
$I_D @ T_C = 25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V^1$	-5.8	A
$I_D @ T_C = 100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V^1$	-3.5	A
I_{DM}	Pulsed Drain Current ²	-14.8	A
EAS	Single Pulse Avalanche Energy ³	58	mJ
$P_D @ T_C = 25^\circ C$	Total Power Dissipation ⁴	2.13	W
T_{STG}	Storage Temperature Range	-55 to 150	$^\circ C$
T_J	Operating Junction Temperature Range	-55 to 150	$^\circ C$
$R_{\theta JA}$	Thermal Resistance Junction-Ambient ¹	62.5	$^\circ C/W$
$R_{\theta JC}$	Thermal Resistance Junction-Case ¹	5.4	$^\circ C/W$

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Electrical Characteristics ($T_J=25^\circ\text{C}$, unless otherwise noted)

Symbol	Parameter	Test Condition	Min.	Typ	Max.	Units
BVDSS	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_D = -250\mu A$	-100	117	-	V
IDSS	Zero Gate Voltage Drain Current	$V_{DS} = -100V, V_{GS} = 0V$	-	-	1	μA
IGSS	Gate to Body Leakage Current	$V_{DS} = 0V, V_{GS} = \pm 20V$	-	-	± 100	nA
VGS(th)	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = -250\mu A$	-1.2	-1.85	-2.5	V
RDS(on)	Static Drain-Source On-Resistance ^{note1}	$V_{GS} = -10V, I_D = -5A$	-	250	300	m Ω
		$V_{GS} = -4.5V, I_D = -3A$	-	260	340	
Ciss	Input Capacitance	$V_{DS} = -50V, V_{GS} = 0V,$ $f = 1.0MHz$	-	760	-	pF
Coss	Output Capacitance		-	25	-	pF
Crss	Reverse Transfer Capacitance		-	12	-	pF
Qg	Total Gate Charge	$V_{DD} = -50V, I_D = -5A,$ $V_{GS} = -10V$	-	11.5	-	nC
Qgs	Gate-Source Charge		-	1.3	-	nC
Qgd	Gate-Drain("Miller") Charge		-	2.9	-	nC
td(on)	Turn-On Delay Time	$V_{DS} = -50V, I_D = -5A$ $R_G=4.5\Omega, R_L=25\Omega$ $V_{GEN} = -10V$	-	12	-	ns
tr	Turn-On Rise Time		-	5	-	ns
td(off)	Turn-Off Delay Time		-	35	-	ns
tf	Turn-Off Fall Time		-	20	-	ns
IS	Maximum Continuous Drain to Source Diode Forward Current		-	-	-12.8	A
VSD	Drain to Source Diode Forward Voltage	$V_{GS} = 0V, I_S = -1A$	-	-	-1.3	V
trr	Reverse Recovery Time	$V_{GS} = 0V, I_{sd} = -3A, di/dt$ $= 100A/\mu s$	-	25	-	nS
Qrr	Reverse Recovery Charge		-	20	-	nC

Note :

1. The data tested by surface mounted on a 1 inch 2 FR-4 board with 2OZ copper.
2. The data tested by pulsed , pulse width .The EAS data shows Max. rating .
3. The power dissipation is limited by 175°C junction temperature
4. The data is theoretically the same as ID and IDM , in real applications , should be limited by total power dissipation.

Typical Characteristics

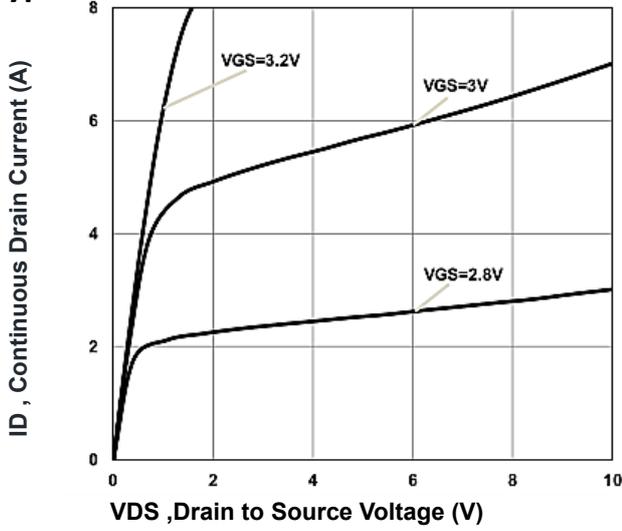


Figure 1. Typical Output Characteristics

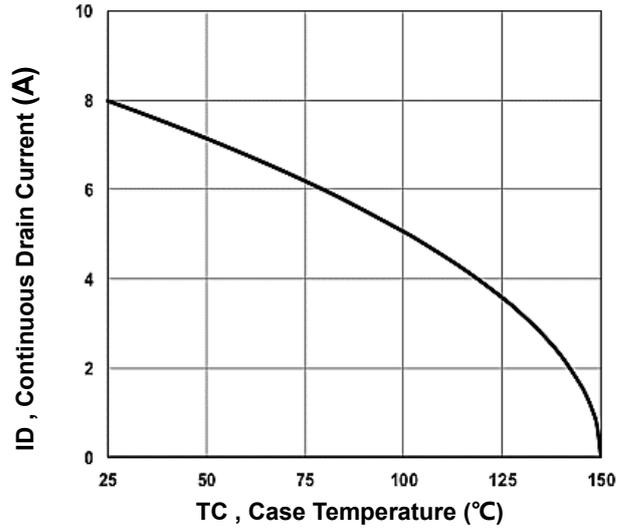


Figure 2. Continuous Drain Current vs. TC

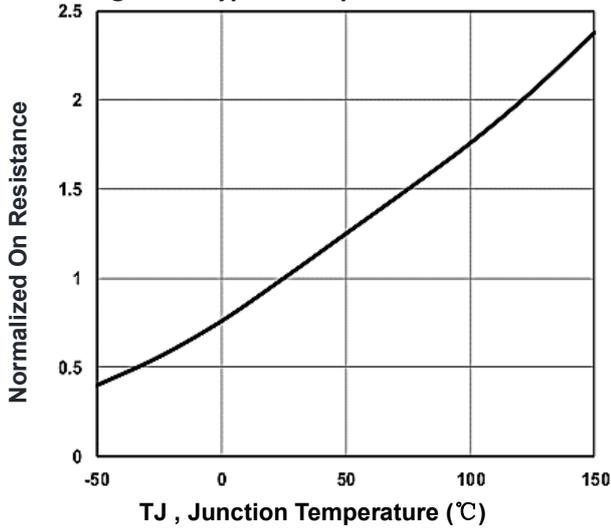


Figure 3. Normalized RDS(on) vs. TJ

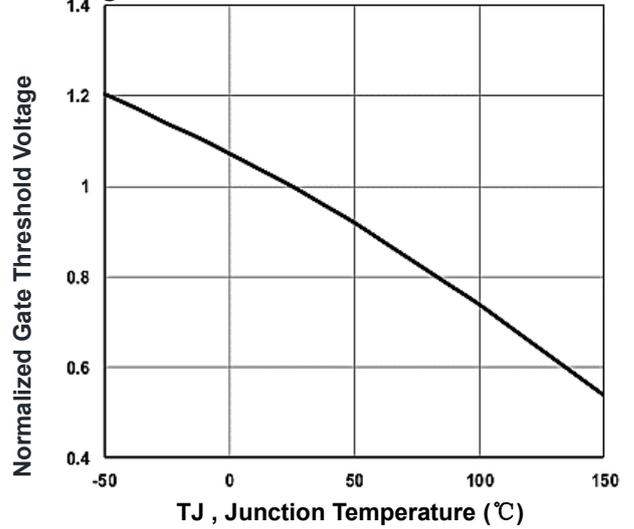


Figure 5. Normalized V_{th} vs. T

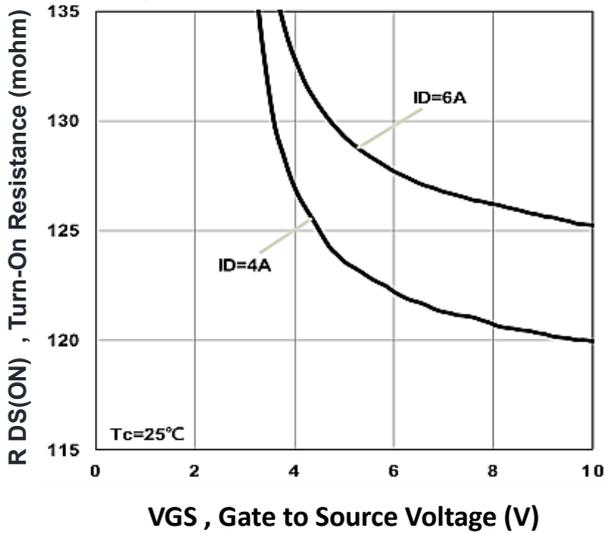


Figure 6. Turn-On Resistance vs. VGS

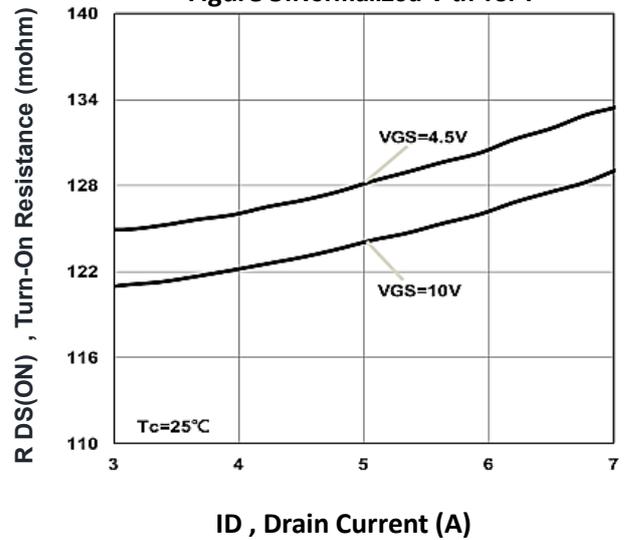
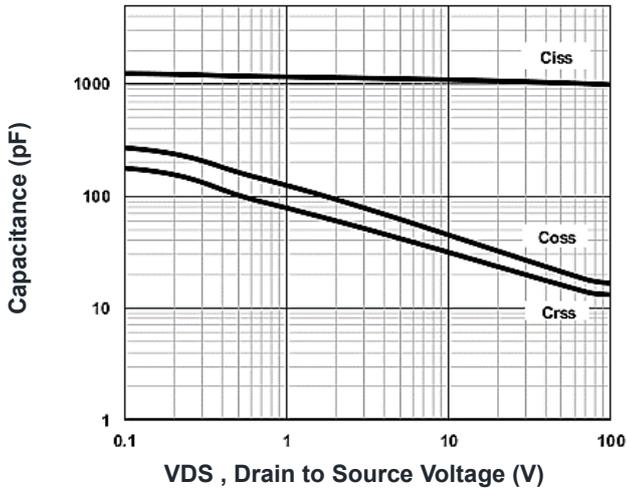
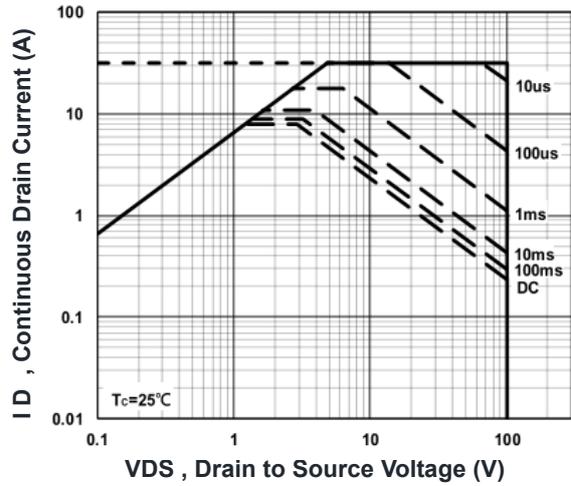


Figure 7. Turn-On Resistance vs. I_D

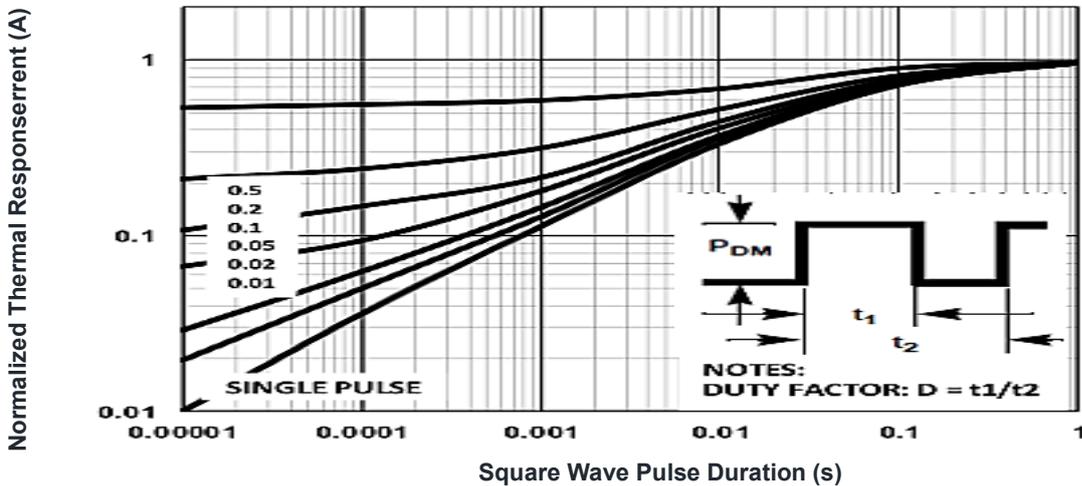
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VDS , Drain to Source Voltage (V)
Figure 8. Capacitance Characteristics



VDS , Drain to Source Voltage (V)
Figure 9. Maximum Safe Operation Area



Square Wave Pulse Duration (s)
Figure 10. Normalized Transient Impedance

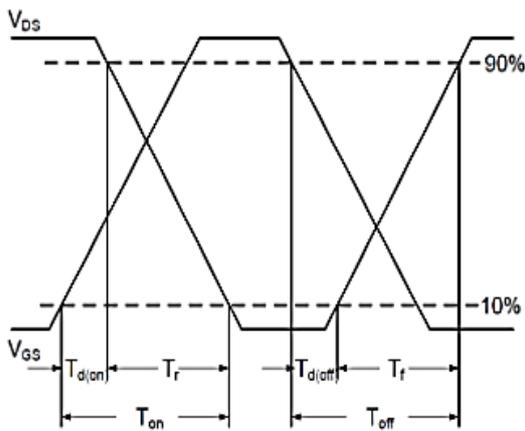


Figure 10. Switching Time Waveform

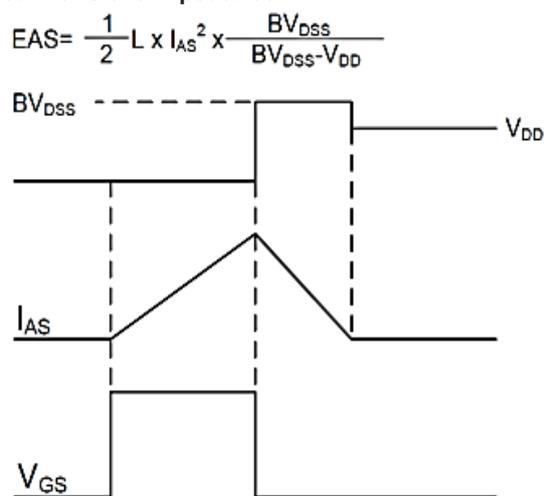
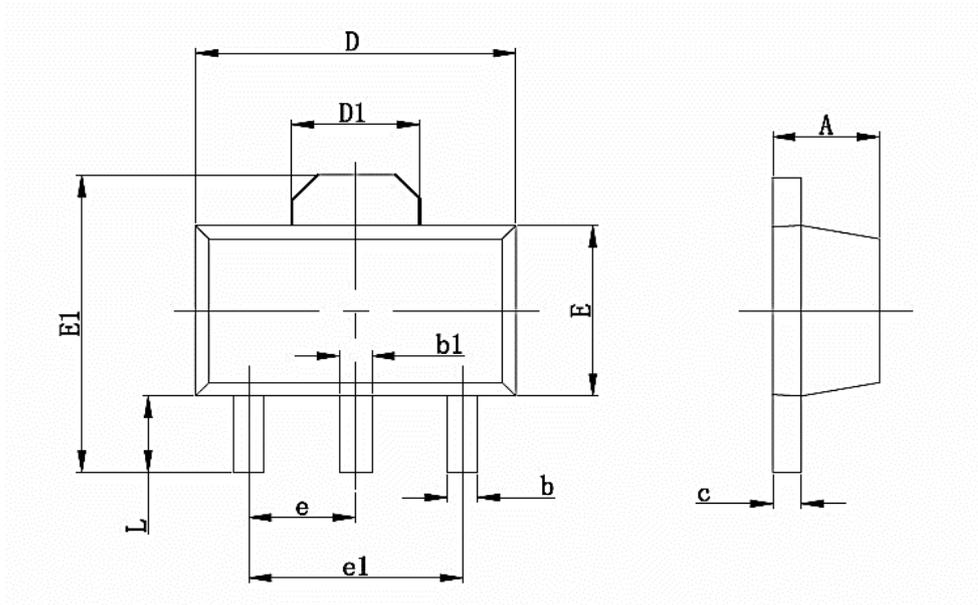


Figure 11. Unclamped Inductive Switching Waveform

$$EAS = \frac{1}{2} L \times I_{AS}^2 \times \frac{BV_{DSS}}{BV_{DSS} - V_{DD}}$$

Package Mechanical Data:SOT89-3L



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min	Max	Min	Max
A	1.400	1.600	0.055	0.063
b	0.350	0.520	0.013	0.197
b1	0.400	0.580	0.016	0.023
c	0.350	0.440	0.014	0.017
D	4.400	4.600	0.173	0.181
D1	1.550 REF		0.061 REF	
E	2.350	2.550	0.091	0.102
E1	3.940	4.250	0.155	0.167
e	1.500 TYP		0.060TYP	
e1	3.000 TYP		0.118TYP	
L	0.900	1.100	0.035	0.047

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Edition	Date	Change
Rve1.0	2022/3/10	Initial release

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